

# *In-situ/Operando* (S)TEM on Mass Selected Pt Clusters Deposited on CeO<sub>2</sub> for CO Oxidation Catalysis

Ajai Raj Lakshmi Nilayam<sup>1</sup>, Ramin Shadkam<sup>1</sup>, Carina Babu Maliakkal<sup>1</sup>, Mohana Veerraju Kante<sup>1</sup>, Horst Hahn<sup>1</sup>, Di Wang<sup>1</sup>, Christian Kübel<sup>1,2</sup>

<sup>1</sup>Institute of Nanotechnology, Karlsruhe Institute of Technology, 76344 Eggenstein-Leopoldshafen, Germany

<sup>2</sup>Karlsruhe Nano Micro Facility (KNMFi), Karlsruhe Institute of Technology, 76344 Eggenstein-Leopoldshafen, Germany

Email: ajai.nilayam@kit.edu

The study of model catalyst systems with mass selected Pt, Pd and Pt-Pd clusters on nanostructured metal oxide supports like CeO<sub>2</sub>, Al<sub>2</sub>O<sub>3</sub> in exhaust gas environments can be helpful to understand the fundamental processes in catalytic reactions of exhaust gases, to unravel the complex relationship between the structure and the catalytic properties. *In-situ* TEM can be of aid to track the dynamic transient stages involved such as structural or morphological changes of clusters under catalytic reaction conditions. In this work the behavior of size selected Pt clusters (50-200 atoms) deposited on CeO<sub>2</sub> support are studied using advanced scanning transmission electron microscopy (STEM) techniques, under pure gas environments (H<sub>2</sub>, Ar, O<sub>2</sub>, CO, CO<sub>2</sub>) and during CO oxidation (with CO and O<sub>2</sub>).

Size selected Pt clusters are deposited using an ultra high vacuum (UHV) cluster ion beam deposition (CIBD) system<sup>1</sup> on top CeO<sub>2</sub> thin films, which is deposited on *in-situ* TEM nanoreactors. Pt clusters are characterized calculating the pair distribution function from 4D-STEM datasets. The morphology changes in the clusters, cluster-support interaction, cluster-gas interaction etc. are studied realtime in pretreatment and exhaust gas environments using *in-situ* STEM imaging & spectroscopy. The CO<sub>2</sub> generation and the level of conversion at different temperatures can be qualitatively studied using high sensitivity residual gas analyzer (RGA). Figure 1(a) shows the 4D-STEM image of Pt<sub>55</sub> deposited directly onto Si<sub>3</sub>N<sub>4</sub>. The integrated PDF of all Pt<sub>55</sub> clusters is compared to the PDFs simulated for Pt<sub>55</sub>-FCC and Pt<sub>55</sub>-icosahedron (Fig. 1(b)).

*In-situ* (S)TEM on Pt<sub>200</sub> supported on CeO<sub>2</sub> at pretreatment conditions (oxidation and reduction cycles at 300-500°C) are done and the clusters are found stable at both reducing and oxidative atmospheres. The clusters dynamics under catalytic reaction conditions (in CO & O<sub>2</sub> atmospheres) are tracked *in-situ* at different temperatures from 200-700°C. With continuous imaging, the clusters are found hopping through CeO<sub>2</sub>, sintering only at 200-300°C. The movement is not identified at higher temperatures when tracked with the electron beam. Clusters in the areas which are not tracked with e<sup>-</sup> beam are found coalesced, moved to other locations at higher temperatures. This shows that the effect of the electron beam on the reaction sites are inevitable and has to be taken into account during acquisition.

To summarize, the study concentrates on the structural characterization of Pt clusters using 4D-STEM PDF. The results show clear differences from bulk FCC-Pt and more resemble towards isomeric shapes. Comparison of PDFs of Pt<sub>55</sub> icosahedron at various orientations confirms shift of pair distances and intensity variations according to the changes in diffraction intensities with different orientation. Additionally, *in-situ* evaluation of the model catalyst system shows changes in the morphology as well as movement and sintering of the clusters on CeO<sub>2</sub> under catalytic reaction conditions.

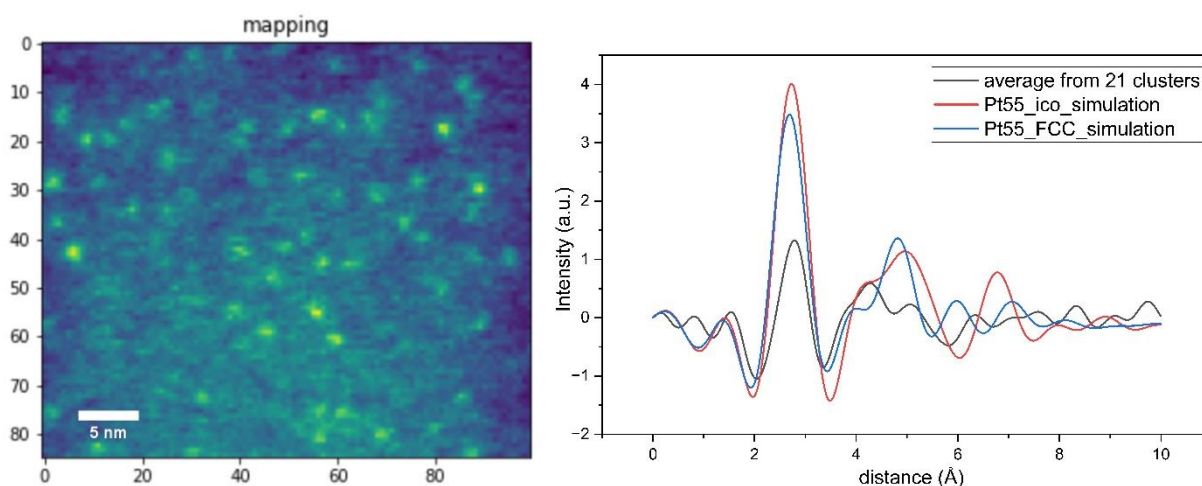


Fig 1: a) 4D-STEM map of Pt<sub>55</sub> clusters on Si<sub>3</sub>N<sub>4</sub>, b) Comparison of background subtracted Pt<sub>55</sub> PDF with Pt<sub>55</sub>-FCC and Pt<sub>55</sub>-ico simulated PDFs

## Reference:

1. A. Fischer, R. Kruk, H. Hahn, *Rev Sci Instrum* **2015**, 86, (2), 023304, <https://doi.org/10.1063/1.4908166>
2. K. E. A. Batista, M. J. Piotrowski, A. S. Chaves, J. L. F. D. Silva, *J. Chem. Phys.* **2016**, 144, 054310, <https://doi.org/10.1063/1.4941295>